

ABSTRACT

ANISOTROPIC CONDUCTIVE FILM, PRODUCTION METHOD THEREOF AND METHOD OF USE THEREOF

The present invention provides an anisotropic conductive film for testing an electronic component, which comprises a
5 film substrate comprising an insulating resin and plural
conductive paths insulated from each other and penetrating the
film substrate in the thickness direction, preferably, an
anisotropic conductive film wherein the plural conductive
paths are disposed in a houndstooth check pattern and the
10 distance between conductive paths between adjacent rows of
conductive paths is smaller than the distance between
conductive paths within a row of conductive paths. In another
preferable embodiment, the insulating resin comprises a
naphthalene skeleton epoxy resin crosslinked with a phenol
15 resin and an acrylic rubber, and both ends of the plural
conductive paths are exposed on both the front and the back
surfaces of the film substrate.